

**Silicon Carbide  
PiN Diode Chip**

$V_{RRM}$	=	8000 V
$I_F @ 25\text{ }^\circ\text{C}$	=	2 A

**Features**

- 8 kV blocking
- 210 °C operating temperature
- Fast turn off characteristics
- Soft reverse recovery characteristics
- Ultra-Fast high temperature switching



Die Size = 2.4 mm x 2.4 mm

**Advantages**

- Reduced stacking
- Reduced system complexity/Increased reliability

**Applications**

- Voltage Multiplier
- Ignition/Trigger Circuits
- Oil/Downhole
- Lighting
- Defense

**Maximum Ratings at  $T_j = 210\text{ }^\circ\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Values	Unit
Repetitive peak reverse voltage	$V_{RRM}$		8	kV
Continuous forward current	$I_F$		2	A
RMS forward current	$I_{F(RMS)}$		1	A
Operating and storage temperature	$T_j, T_{stg}$		-55 to 210	$^\circ\text{C}$

**Electrical Characteristics at  $T_j = 210\text{ }^\circ\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Diode forward voltage	$V_F$	$I_F = 2\text{ A}, T_j = 25\text{ }^\circ\text{C}$		6.1		V
		$I_F = 2\text{ A}, T_j = 210\text{ }^\circ\text{C}$		4.3		
Reverse current	$I_R$	$V_R = 8\text{ kV}, T_j = 25\text{ }^\circ\text{C}$		4		$\mu\text{A}$
		$V_R = 8\text{ kV}, T_j = 175\text{ }^\circ\text{C}$		4		
Total reverse recovery charge	$Q_{rr}$	$I_F \leq I_{F,MAX}$ $di_F/dt = 70\text{ A}/\mu\text{s}$ $T_j = 210\text{ }^\circ\text{C}$	$V_R = 1000\text{ V}$ $I_F = 1.5\text{ A}$	558		nC
Switching time	$t_s$		$V_R = 1000\text{ V}$ $I_F = 1.5\text{ A}$	< 236		ns
Total capacitance	C	$V_R = 1\text{ V}, f = 1\text{ MHz}, T_j = 25\text{ }^\circ\text{C}$		26		pF
		$V_R = 400\text{ V}, f = 1\text{ MHz}, T_j = 25\text{ }^\circ\text{C}$		5		
		$V_R = 1000\text{ V}, f = 1\text{ MHz}, T_j = 25\text{ }^\circ\text{C}$		4		
Total capacitive charge	$Q_C$	$V_R = 1000\text{ V}, f = 1\text{ MHz}, T_j = 25\text{ }^\circ\text{C}$		5.4		nC

Figures:

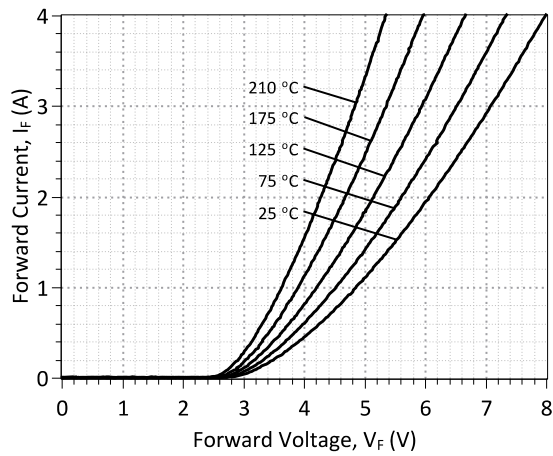


Figure 1: Typical Forward Characteristics

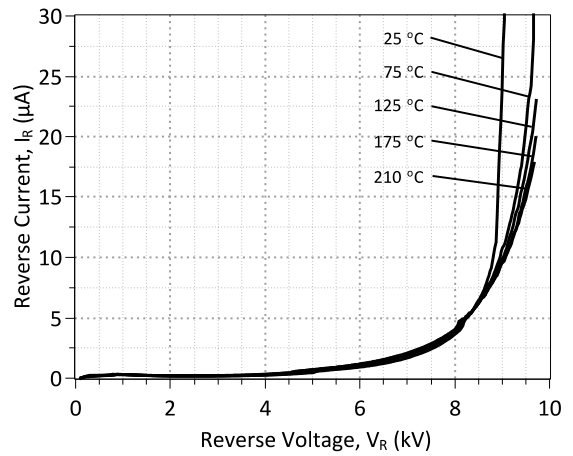


Figure 2: Typical Reverse Characteristics at 25°C

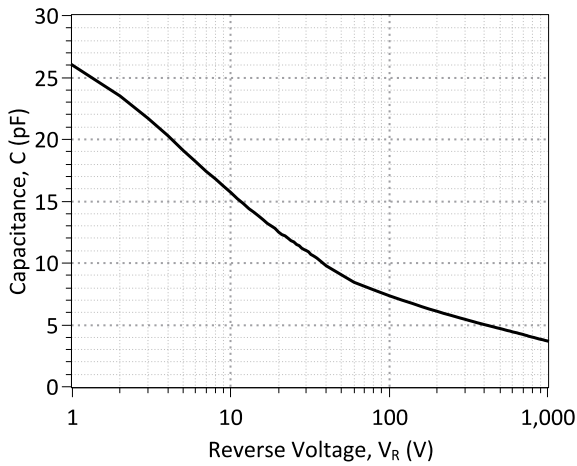


Figure 3: Typical Junction Capacitance vs Reverse Voltage Characteristics

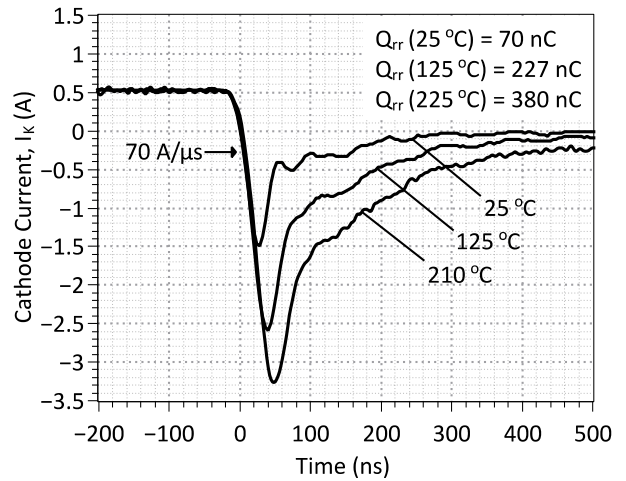


Figure 4: Typical Turn Off Characteristics at  $I_k = 0.5 \text{ A}$  and  $V_R = 1000 \text{ V}$

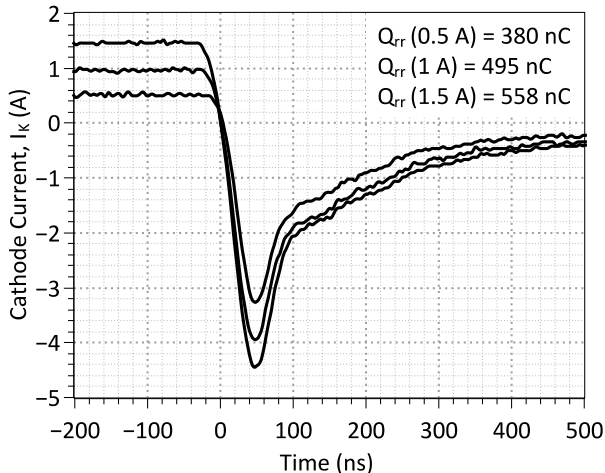


Figure 5: Typical Turn Off Characteristics at  $T_j = 210 \text{ °C}$  and  $V_R = 1000 \text{ V}$

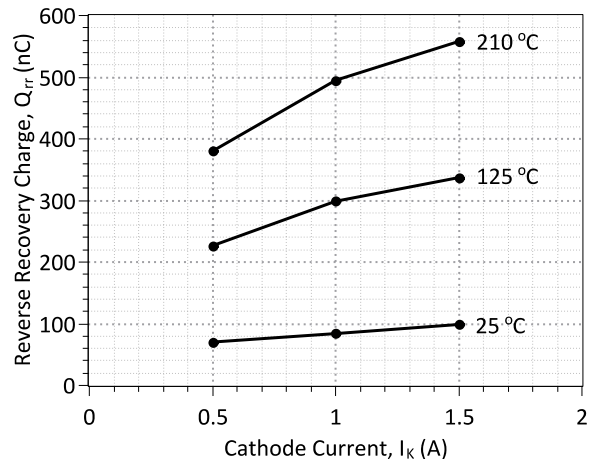


Figure 6: Reverse Recovery Charge vs Cathode Current

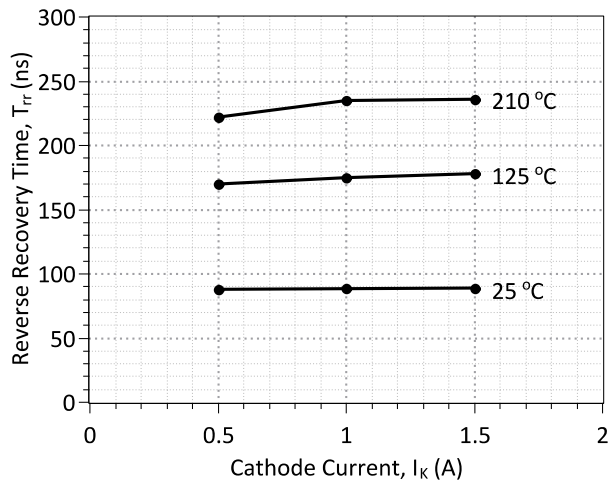
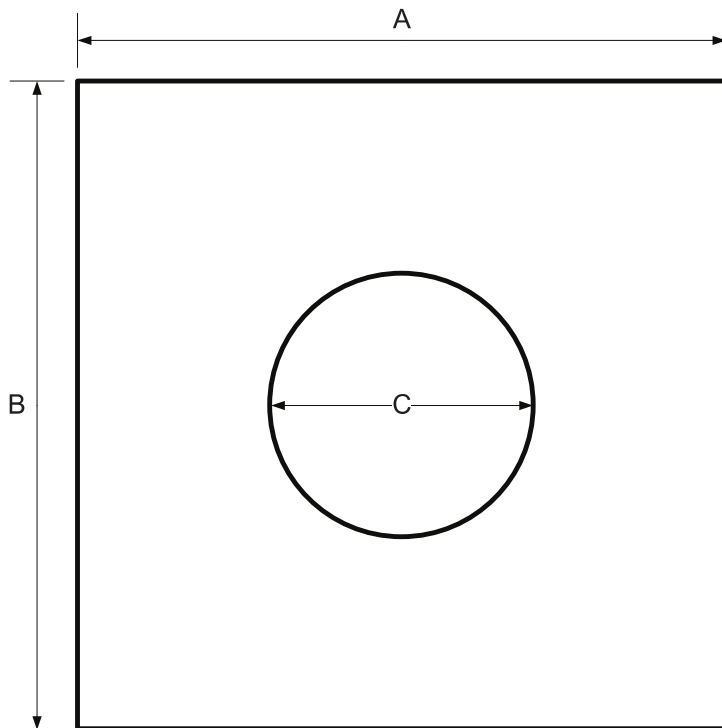


Figure 7: Reverse Recovery Time vs Cathode Current

**Mechanical Parameters**

Die Dimensions	2.4 x 2.4	mm <sup>2</sup>
Anode pad size	Φ 0.98	mm
Area total / active	5.76/0.75	mm <sup>2</sup>
Die Thickness	450	μm
Wafer Size	76.2	mm
Flat Position	0	deg
Die Frontside Passivation	Polyimide	
Anode Pad Metallization	400 nm Ni + 200 nm Au	
Backside Cathode Metallization	400 nm Ni + 200 nm Au	
Die Attach	Electrically conductive glue or solder	
Wire Bond	Au ≤ 26 μm	
Reject ink dot size	Φ ≥ 0.3 mm	
Recommended storage environment	Store in original container, in dry nitrogen, < 6 months at an ambient temperature of 23 °C	

**Chip Dimensions:**



DIE	A [mm]	2.4
	B [mm]	2.4
METAL	C [mm]	0.98

**Revision History**

Date	Revision	Comments	Supersedes
2015/04/30	2	Updated Electrical Characteristics	
2015/02/25	1	Inserted Mechanical Parameters	
2013/11/27	0	Initial release	

Published by

GeneSiC Semiconductor, Inc.  
43670 Trade Center Place Suite 155  
Dulles, VA 20166

GeneSiC Semiconductor, Inc. reserves right to make changes to the product specifications and data in this document without notice.

GeneSiC disclaims all and any warranty and liability arising out of use or application of any product. No license, express or implied to any intellectual property rights is granted by this document.

Unless otherwise expressly indicated, GeneSiC products are not designed, tested or authorized for use in life-saving, medical, aircraft navigation, communication, air traffic control and weapons systems, nor in applications where their failure may result in death, personal injury and/or property damage.

## SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website ([http://www.genesicsemi.com/images/hit\\_sic/baredie/pin/GA01PNS80-CAU\\_SPICE.pdf](http://www.genesicsemi.com/images/hit_sic/baredie/pin/GA01PNS80-CAU_SPICE.pdf)) into LTSPICE (version 4) software for simulation of the GA01PNS80-CAU device.

```
*      MODEL OF GeneSiC Semiconductor Inc.
*
*      $Revision:   1.1           $
*      $Date:      30-APR-2015   $
*
*      GeneSiC Semiconductor Inc.
*      43670 Trade Center Place Ste. 155
*      Dulles, VA 20166
*
*      COPYRIGHT (C) 2013 GeneSiC Semiconductor Inc.
*      ALL RIGHTS RESERVED
*
*      These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
*      OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
*      TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
*      PARTICULAR PURPOSE."
*      Models accurate up to 2 times rated drain current.
*
*      Start of GA01PNS80-CAU SPICE Model
*
. MODEL GA01PNS80 D
+ IS      9.2491e-015
+ RS      1.02512
+ N       3.3373
+ IKF     0.00011784
+ EG      3.23
+ XTI     25
+ TRS1    -0.0024
+ CJO     2.7E-11
+ VJ      2.304
+ M       0.376
+ FC      0.5
+ BV      8000
+ IBV     1.00E-03
+ VPK     8000
+ IAVE    1
+ TYPE    SiC_PiN
+ MFG     GeneSiC_Semi
*
*      End of GA01PNS80-CAU SPICE Model
```